

<b>Search Notes</b> 	<b>Application/Control No.</b>	<b>Applicant(s)/Patent under Reexamination</b>
	10/529,732	DE VAAN, ADRIANUS JOHANNES STEPHANES MA
<b>Examiner</b>	<b>Art Unit</b>	
Andrew Kong	2851	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
w/ <del>Sec. W</del>	<del>7/16/01</del>	<del>WD</del>	